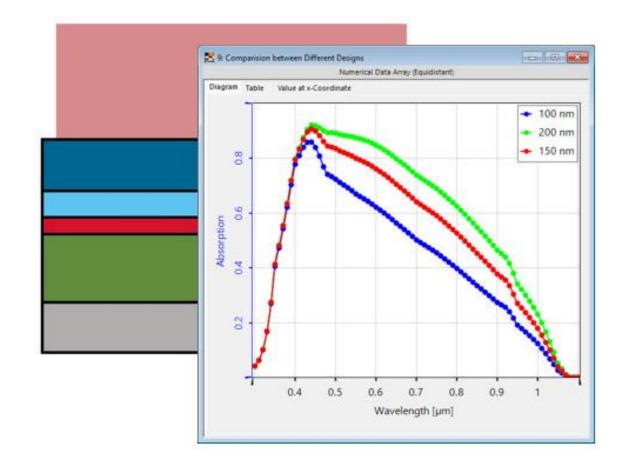


#### Absorption in a CIGS Solar Cell

#### **Abstract**



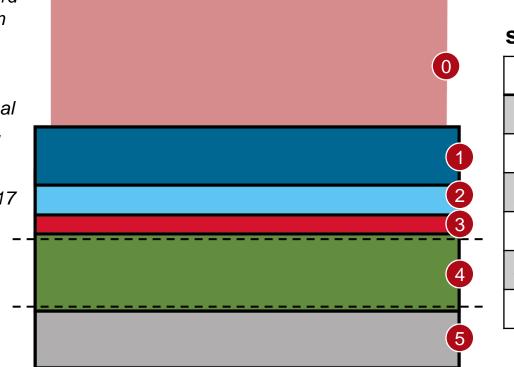
Solar cells are a fundamental technology in the field of renewable energy. To optimize efficiency, most common designs use thin-layer structures and media with high absorption coefficients as it is precisely this absorbed optical energy what will eventually be transformed into an electric current. Solar cells based on copper indium gallium selenide (CIGS) have become quite common as they can be made much thinner without losing absorption efficiency, compared with cells based on other materials.

# **Modeling Task**

#### plane wave

homogeneous spectrum from 300nm to 1100nm

System from: J. Goffard et al., "Light Trapping in Ultrathin CIGS Solar Cells with Nanostructured Back Mirrors," in IEEE Journal of Photovoltaics, vol. 7, no. 5, pp. 1433-1441, Sept. 2017, doi: 10.1109/JPHOTOV.2017 .2726566.



#### detectors

radiant flux (absorbed power will be calculated as the difference between the radiant flux readings of both detectors)

#### solar cell

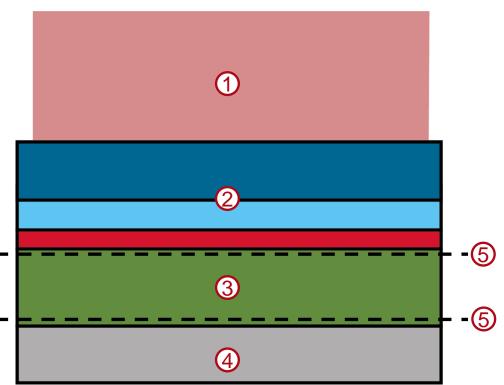
| no. | material      | thickness     |
|-----|---------------|---------------|
| 0   | fused silica* | -             |
| 1   | ZnO:Al        | 100nm         |
| 2   | i-ZnO         | 70nm          |
| 3   | ZnS           | 50nm          |
| 4   | CIGS          | 100/150/200nm |
| 5   | molybdenum    | substrate     |

\* We assume that the solar cell is protected by a layer of fused silica with anti-reflection coating.

# **Single-Platform Interoperability of Modeling Techniques**

Light will encounter and interact with different components as it propagates through the system. A suitable model that provides a good compromise between accuracy and speed is required for each of these elements of the system:

- 1 source
- 2 solar cell layer
- 3 CIGS layer
- 4 Substrate
- **(5)** detector

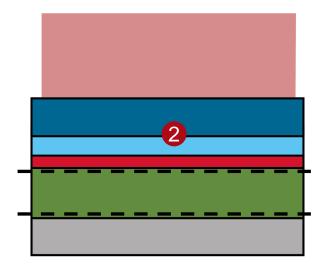


### **Connected Modeling Techniques: Solar Cell Layers**

source
 solar cell layers
 CIGS layer
 substrate
 detectors

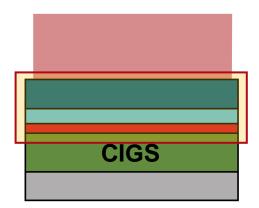
Available modeling techniques for multi-layer systems:

| Methods                                    | Preconditions                       | Accuracy | Speed     | Comments   |
|--|-------------------------------------|----------|-----------|--|
| FMM/RCWA                                   | none                                | high     | high      | rigorous model; includes<br>evanescent waves; k-<br>domain |
| S-matrix                                   | planar surface                      | high     | very high | rigorous model; includes<br>evanescent waves; k-<br>domain |
| Local Planar<br>Interface<br>Approximation | surface not in focal region of beam | high     | high      | local application of S<br>matrix; LPIA; x-domain           |



Since the **S-matrix** solver operates entirely in the k-domain, no additional steps for switching between domains (Fourier transforms) are required for the application of this solver. This allows for the fastest possible simulation speed while maintaining a rigorous model.

#### **Stratified Media Component**



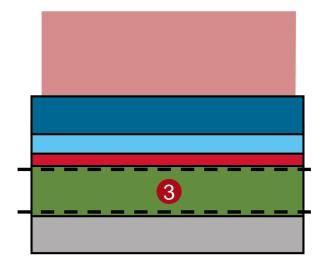
For the layers above the CIGS we employ the *Stratified Media Component*, since it provides a fast and rigorous solution for x, yinvariant layer stacks.

| Edit Stratified Media     | a Component  |             |   | ×                         |                                |                   |   |
|---------------------------|--|-------------|---|---------------------------|--------------------------------|-------------------|---|
| Coordinate<br>Systems     | Component Size 20 mm ×<br>Reference Surface (all Channels)<br>Plane Surface  | Edit Parame | 20 mm   |                           |                                | >                 | < |
| Position /<br>Orientation | Aperture O Yes O No Coating Name Standard Coating                            | Layer Defin | Index: 1<br>2<br>3<br>4                         |                           |                                | Coating<br>Layers |   |
|                           | Coating Orientation ← Front Side Application ←                               | Index       | Thickness                                       | Distance                  |                                | Material          | 1 |
| Solver                    | Homogeneous Medium Behind Surface<br>CIGS in Homogeneous Medium<br>CiGS Load | 1<br>2<br>3 | 50 nm<br>70 nm<br>100 nm                        | 50 nm<br>120 nm<br>220 nm |                                | <u> </u>          |   |
| Fourier<br>Transforms     | уг. 🕑  |             | d<br>Igth Range of M<br>Im Wavelength<br>300 nm | Maximum V                 | Delet<br>Vavelength<br>.125 µm | te Layer Tools 🔻  |   |
|                           |  | ۹ 🔒         | 1   |                           | OK                             | Cancel Help       |   |

### **Connected Modeling Techniques: CIGS Layers**

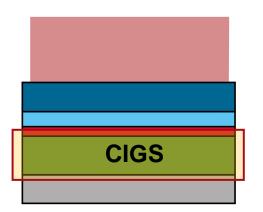
source
 solar cell layer
 CIGS layer
 substrate
 detectors

| Methods                            | Preconditions   | Accuracy | Speed     | Comments   |  |  |
|------------------------------------|-----------------|----------|-----------|--|--|--|
| Rayleigh<br>Sommerfeld<br>Integral | none            | high     | low       | rigorous solution  |  |  |
| Fourier<br>Domain<br>Techniques    | none            | high     | high      | rigorous mathematical<br>reformulation of RS<br>integral |  |  |
| Fresnel                            | paraxial        | high     | high      | assumes paraxial light;                                  |  |  |
| Integral                           | non-paraxial    | low      | high      | moderate speed for<br>very short distances               |  |  |
| Geometric                          | low diffraction | high     | very high | neglects diffraction                                     |  |  |
| Propagation                        | otherwise       | low      | very high | effects  |  |  |

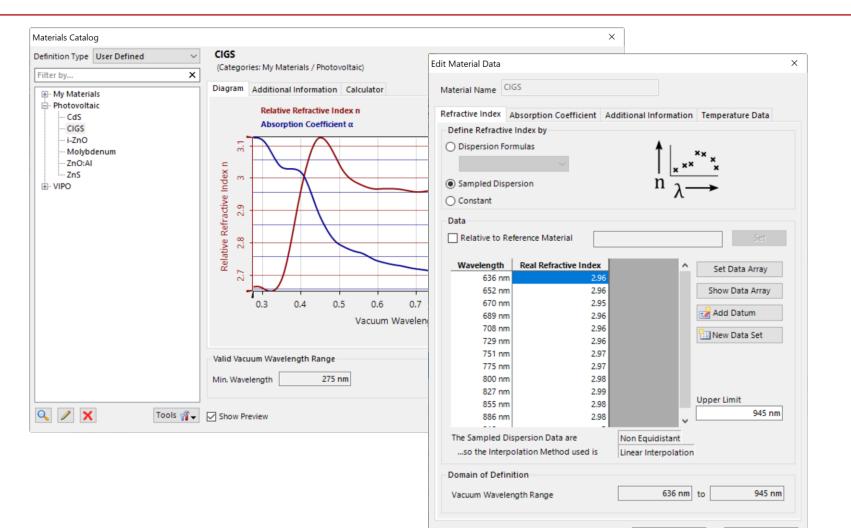


The CIGS layer itself can be modeled by a single free-space propagation step in the corresponding homogeneous medium. Due to diffraction does not add any significant effects here, **Geometric Propagation** is used.

### **Definition of Materials and Media**



VirtualLab Fusion offers a comprehensive database of different materials that can, among other things, be used for coatings. But it is also possible to import material data from measurements, like ellipsometry.



Usable Vacuum Wavelength Range 🧵

🔍 🛃 Tools 🎲 🗸 Validity: 🚹 📋

636 nm to

Cancel

Ok

925 nm

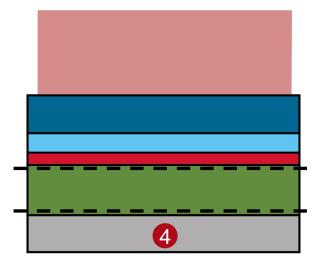
Help

### **Connected Modeling Techniques: Substrate**

source
 solar cell laye
 CIGS layer
 substrate
 detectors

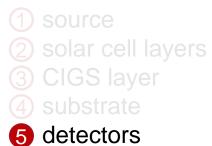
Available modeling techniques for interaction with surface:

| Methods                                    | Preconditions                       | Accuracy          | Speed | Comments   |
|--|-------------------------------------|-------------------|-------|--|
| functional<br>approach                     | -                                   | no Fresnel losses |       |  |
| S-matrix                                   | planar surface                      | high              | high  | rigorous model; includes<br>evanescent waves; k-<br>domain |
| Local Planar<br>Interface<br>Approximation | surface not in focal region of beam | high              | high  | local application of S<br>matrix; LPIA; x-domain           |



For our simulation, only the reflection of the substrate is of interest, reducing the problem to an interaction with a single surface. Here, **Local Planar Interface Approximation** provides the best compromise between speed and accuracy.

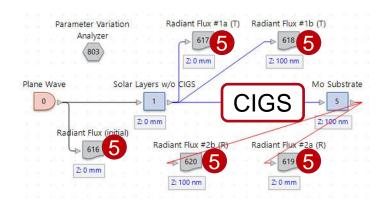
# **Connected Modeling Techniques: Detectors**

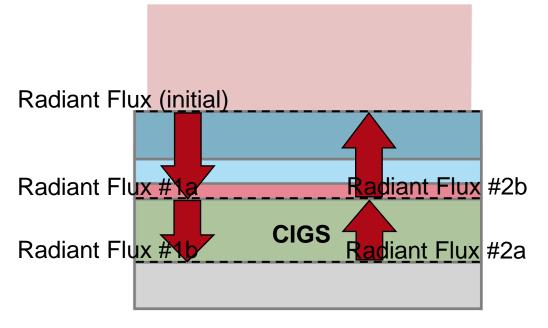


The absorbed energy inside the CIGS layer per wavelength is determined by adding/subtracting the values of the radiant flux from 4 different *Universal Detectors*: before the CIGS layer: 1a(Transmitted part) and 2a(Reflected part), behind: 1b and 2b.

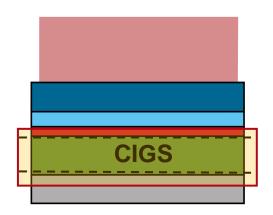
absorped energy 
$$= 1b - 1a + 2b - 2a$$

These values are then normalized by the initial radiant flux to get the absorption ratio.





#### **Parameter Variation Analyzer**

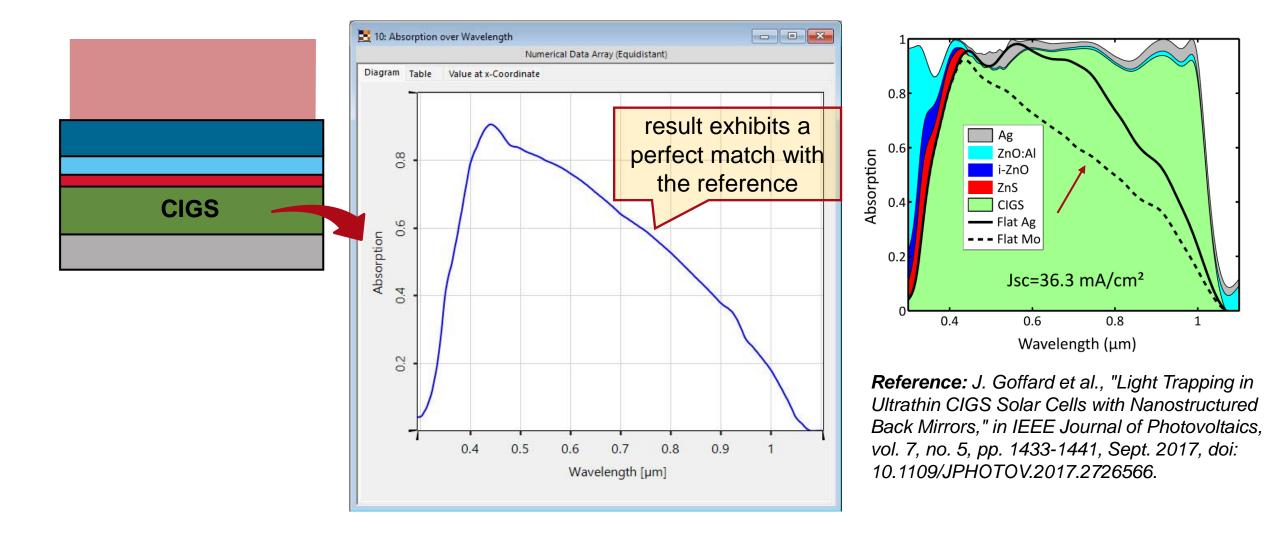


With the Parameter Variation Analyzer, the addition/subtraction can be done automatically, outputting the resulting absorption by a single simulation. For more information, see:

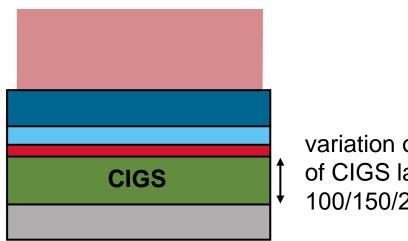
Parameter Variation Analyzer

| 10 6: Ed  | lit Paramete                | r Variat   | ion                         |   |  |  |  |  |                                  | <u> </u>                 |        | ×        |           |            |
|-----------|-----------------------------|--|-----------------------------|---|--|--|--|--|----------------------------------|--------------------------|--------|----------|-----------|------------|
| Paramet   | ter Specifica               | tion   |                             |   |  |  |  |  |                                  |                          |        |          |           |            |
| Set up th | h <mark>e para</mark> meter | (s) to b   | e varied.                   |   |  |  |  |  |                                  |                          |        |          |           |            |
| specifyir |                             | aramet   | parameters whers are varied |   | ed as we                                 | ll as the re                                 | sulting nun                                      | nber of ite                                  | rations. Severa                  | al <u>modes</u> are ava  | ilable |          |           |            |
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| 1 2 *     | Object<br>"Plane Wave       |  | Category                    | Parameter<br>Wavelength   | Vary                                     | From<br>300 nm                               | 1.1 μm   | Steps<br>81                                  | Step Size                        | Original Value<br>900 nm | e      |          |           |            |
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#### **Absorption for Different Thicknesses of the CIGS Layer**

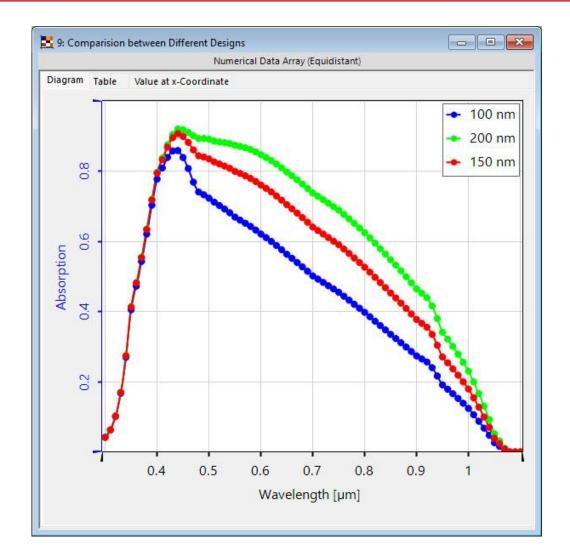


# **Absorption for Different Thicknesses of the CIGS Layer**



variation of thickness of CIGS layer: 100/150/200nm

The thickness of the absorbing material is one of the most important parameters affecting the overall efficiency of the cell.



| title            | Absorption in a CIGS Solar Cell  |
|------------------|--|
| document code    | MISC.0096  |
| document version | 1.1  |
| software edition | VirtualLab Fusion  |
| software version | 2023.2 (Build 1.242)   |
| category         | Application Use Case   |
| further reading  | <ul> <li><u>Stratified Media Component</u></li> <li><u>Parameter Variation Analyzer</u></li> </ul> |